S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/072,939	WEI ET AL.	
Examiner	Art Unit	
John B. Strege	2625	

· SEARCHED			
Class	Subclass	Date	Examiner
382	274,181 190,195 206,299 300,118	11/16/2005	JS
382	131	11/16/2005	JS
update	d	5/9/06	JS
update Upda	ted	8117/06	15
			•
		-	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			•

SEARCH (INCLUDING SEAR		n
	DATE	EXMR
SEE EAST Search PLUS Search Included INSPEC Search IEEE Search	11/16/2005	JS
vpdated crdated:	5A106 \$11706	35 7 S
•		
	·	